A mathematical model for the determination of lekage in mains and water distribution networks
Koppel, Tiit; **Ainola, Leo**; **Puust, Raido** Proceedings of the Estonian Academy of Sciences. Engineering 2007 / 1, p. 3-16 : ill

A new measure for calculating multiple fault coverage of microprocessor self-test
Oyeniran, Adeboye Stephen; **Odozi, Uzochukwu Eddie**; **Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

A novel artificial neural networks based automatic adaptive fault detection technique for analog circuits
Petlenkov, Eduard; **Jutman, Artur**; **Nõmm, Sven**; **Ubar, Raimund-Johannes** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 167-170 : ill

A scalable technique to identify true critical paths in sequential circuits
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings 2017 IEEE 20th International Symposium on Design and Diagnotics of Electronic Circuit & Systems(DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553

A synthesis-agnostic behavioral fault model for high gate-level fault coverage
Karputkin, Anton; **Raik, Jaan** Proceedings of the 2016 Design, Automation & Test in Europe Conference & Exhibition (DATE) : 14-18 March 2016, ICC, Dresden, Germany 2016 / p. 1124-1127 : ill https://ieeexplore.ieee.org/document/7459477/figures#figures

A tool for random test generation targeting high diagnostic resolution
Osimiry, Emmanuel Ovie; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.ester.ee/record=b2150914*est

A tool set for teaching design-for-testability of digital circuits
Kostin, Sergei; **Orasson, Elmet**; **Ubar, Raimund-Johannes** EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill http://dx.doi.org/10.1109/EWME.2016.7496466

Accelerating transient fault injection campaigns by using Dynamic HDL Slicing
Bagbaba, Ahmet Cagri; **Jenihhin, Maksim**; **Raik, Jaan**; Sauer, Christian 2019 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC), 29-30 October 2019, Helsinki, Finland : proceedings in IEEE Xplore 2019 / 7 p. : ill https://doi.org/10.1109/NORCHIP.2019.8906932

Active power losses in Estonian power transmission network
Ainsaar, Karin Maria; **Ülavere, Eero**; **Tammoja, Heiki**; **Valtin, Juhan** 14th International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. II" : Pärnu, Estonia, January 13-18, 2014 2014 / p. 112-117 : ill

Adaptive Kalman filter based data aggregation in fault-resilient Underwater Sensor Networks
Vihman, Lauri; **Raik, Jaan** 2023 24th International Conference on Digital Signal Processing (DSP) 2023 / p. 1-5 https://doi.org/10.1109/DSP58604.2023.10167982

Adjusted electrical equivalent circuit model of induction motor with broken rotor bars
Rassõlkin, Anton; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; Petrov, Aleksei; Plokhov, Igor; Kotelnikov, Aleksandr PQ2016 : the 10th International Conference 2016 Electric Power Quality and Supply Reliability Conference (PQ) : August 29-31, 2016, Tallinn, Estonia : proceedings 2016 / p. 213-218 : ill https://doi.org/10.1109/PQ.2016.7724115

Adjusted electrical equivalent circuit model of induction motor with broken rotor bars and eccentricity faults
Petrov, Aleksei; Plokhov, Igor; **Rassõlkin, Anton**; **Vaimann, Toomas**; **Kallaste, Ants**; **Belahcen, Anouar** Proceeding of the 2017 IEEE 11th International Symposium on Diagnostics for Electric Machines, Power Electronics and Drives (SDEMPED) : [Tinos (Greece), August 29 - September 01, 2017] 2017 / p. 58-64 : ill https://doi.org/10.1109/DEMPED.2017.8062334

Advances in machine fault diagnosis
Vaimann, Toomas Applied sciences 2021 / art. 7348, 5 p https://doi.org/10.3390/app11167348 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Advances in machine fault diagnosis
2022 https://doi.org/10.3390/books978-3-0365-5110-4

Advances in machine fault diagnosis
Vaimann, Toomas Advances in machine fault diagnosis 2022 / p. 1-5 https://doi.org/10.3390/app11167348

Air-core sensors operation modes for partial discharge detection and on-line diagnostics in medium voltage networks

Kütt, Lauri; Shafiq, Muhammad; **Mõlder, Heigo**; **Järvik, Jaan**; Lehtonen, Matti Scientific Journal of Riga Technical University. Electrical, control and communication engineering 2013 / p. 5-12 : ill

Algorithms for hierarchical fault simulation in digital systems
Ubar, Raimund-Johannes; **Raik, Jaan**; Klüver, B. Proceedings of the 10th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2003 : Lodz, Poland, 26-28 June 2003 2003 / p. 530-535 : ill

An analytic model for fault diagnosis in power distribution systems considering unreliable alarms
Wang, Chongyu; Pang, Kaiyuan; Zhang, Yong; **Wen, Fushuan**; **Palu, Ivo**; Xiong, Wen; Chen, Minghui; Shang, Huiyu 2020 IEEE Power & Energy Society General Meeting (GM 2020) 2020 / 5 l https://doi.org/10.1109/PESGM41954.2020.9281468

Analysis of common mode and rapidly varying voltage profile on stator current harmonics of an inverter-fed induction motor
Sardar, Muhammad Usman; **Vaimann, Toomas**; **Kütt, Lauri**; **Kallaste, Andres**; **Asad, Bilal**; **Kudelina, Karolina**; **Akbar, Siddique** 2023 IEEE 64th International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON), Riga, Latvia, October 9-10, 2023 : conference proceedings 2023 / 6 p https://doi.org/10.1109/RTUCON60080.2023.10413067

Analysis of grain orientation and defects in Sb2Se3 solar cells fabricated by close-spaced sublimation
Krautmann, Robert; **Spalatu, Nicolae**; Gunder, Rene; Abou-Ras, Daniel; Unold, Thomas; Schorr, Susan; **Oja Acik, Ilona**; **Krunks, Malle** GSFMT Scientific Conference 2021 : Tartu, June 14-15, 2021 : abstracts 2021 / P 17 https://fmtdk.ut.ee/wp-content/uploads/2021/06/GSFMT_abstractbook_2021.pdf

Analysis of grain orientation and defects in Sb2Se3 solar cells fabricated by close-spaced sublimation : [journal article]
Krautmann, Robert; **Spalatu, Nicolae**; Gunder, Rene; Abou-Ras, Daniel; Unold, Thomas; Schorr, Susan; **Krunks, Malle**; **Oja Acik, Ilona** Solar energy 2021 / p. 494-500 https://doi.org/10.1016/j.solener.2021.07.022 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Analysis of the vibration magnitude of an induction motor with different numbers of broken bars
Martinez, Javier; **Belahcen, Anouar**; Muetze, Annette IEEE transactions on industry applications 2017 / p. 2711-2720 : ill http://dx.doi.org/10.1109/TIA.2017.2657478

Anomaly detection and classification in power system state estimation: Combining model-based and data-driven methods
Asefi, Sajjad; Mitrovic, Mile; Cetenovic, Dragan; Levi, Victor; Gryazina, Elena; Terzija, Vladimir Sustainable energy, grids and networks 2023 / art. 101116 https://doi.org/10.1016/j.segan.2023.101116

Assessment of diagnostic test for automated bug localization
Tihhomirov, Valentin; **Tšepurov, Anton**; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes** LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Assessment of electricity supply interruption costs under restricted time and information resources
Raesaar, Peeter; **Tiigimägi, Eeli**; **Valtin, Juhan** Proceedings of the 2006 IASME/WSEAS International Conference on Energy & Environmental Systems : Chalkida, Greece, May 8-10, 2006 2006 / p. 409-415 : ill

Asynchronous fault detection in IEEE P1687 instrument network
Shibin, Konstantin; **Devadze, Sergei**; **Jutman, Artur** IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

At-speed on-chip diagnosis of board-level interconnect faults
Jutman, Artur Ninth IEEE European Test Symposium : ETS 2004 : 23-26 May 2004, Corsica, France : proceedings 2004 / p. 2-7 : ill https://www.researchgate.net/publication/4098807_At-speed_on-chip_diagnosis_of_board-level_interconnect_faults

Automated area and coverage optimization of minimal latency checkers
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Apneet Kaur**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 2017 22nd IEEE European Test Symposium (ETS 2017), Limassol, Cyprus, 22 – 26 May 2017 : proceedings 2017 / p. 7-8 : ill https://doi.org/10.1109/ETS.2017.7968211

Automated identification of application-dependent safe faults in automotive systems-on-a-chips
Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim**; Sauer, Christian Electronics 2022 / art. 319 https://doi.org/10.3390/electronics11030319 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Automated minimization of concurrent online checkers for network-on-chips
Saltarelli, Pietro; **Niazmand, Behrad**; **Hariharan, Ranganathan**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 10th International Symposium on Reconfigurable and Communication-centric Systems-on-Chip (ReCoSoC 2015) : Bremen, 29 June - 1 July 2015 2015 / [8] p. : ill http://dx.doi.org/10.1109/ReCoSoC.2015.7238079

Automated test bench generation for high-level synthesis flow ABELITE
Viilukas, Taavi; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes**; Baranov, Samary Proceedings of IEEE East-West Design & Test Symposium (EWDTS'2011) : Sevastopol, Ukraine, September 9-12, 2011 2011 / p. 13-16 : ill https://ieeexplore.ieee.org/document/6116601

Auvere jaama ehitaja on Enefit Powerile maksnud trahvi juba 130 miljonit
Nikolajev, Jüri err.ee 2022 Auvere jaama ehitaja on Enefit Powerile maksnud trahvi juba 130 miljonit

AWAIT : an ultra-lightweight soft-error mitigation mechanism for network-on-chip links
Janson, Karl; **Pihlak, Rene**; **Azad, Siavoosh Payandeh**; **Niazmand, Behrad**; **Jervan, Gert**; **Raik, Jaan** 2018 13th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC), Lille, France, July 9th-11th, 2018 2018 / p. 1-6 : ill https://doi.org/10.1109/ReCoSoC.2018.8449374

BASTION - board and SoC test instrumentation for Ageing and No Failure Found
Devadze, Sergei MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 77

BASTION : board and SoC test instrumentation for ageing and no failure found
Jutman, Artur; Lotz, Christophe; Larsson, Erik; Sonza Reorda, Matteo; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 115-120 : ill https://doi.org/10.23919/DATE.2017.7926968

Bearing fault analysis of BLDC motor intended for electric scooter application
Kudelina, Karolina; **Asad, Bilal**; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kallaste, Ants** 2021 IEEE 13th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED) 2021 / p. 427-432 https://doi.org/10.1109/SDEMPED51010.2021.9605519

The bearing faults detection methods for electrical machines — the state of the art
Khan, Muhammad Amir; **Asad, Bilal**; **Kudelina, Karolina**; **Vaimann, Toomas**; **Kallaste, Ants** Energies 2023 / art. 296 https://doi.org/10.3390/en16010296

Bidirectional DC circuit breaker with improved performance during commissioning and reclosing
Pogulaguntla, Aditya; Raghavendra I, Venkata; Banavath, Satish Naik; **Chub, Andrii**; Sreekanth, Thamballa; Krishnamoorthy, Harish Sarma 24th European Conference on Power Electronics and Applications (EPE'22 ECCE Europe) 2022 / p. P1-P9 https://ieeexplore.ieee.org/document/9907667

Broken rotor bar fault detection of the grid and inverter-fed induction motor by effective attenuation of the fundamental component
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; **Rassõlkin, Anton**; **Iqbal, Muhammad Naveed** IET electric power applications 2019 / p. 2005–2014 https://doi.org/10.1049/iet-epa.2019.0350 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Broken rotor bar fault diagnostic of inverter fed induction motor using FFT, Hilbert and Park's vector approach
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants** 2018 XIII International Conference on Electrical Machines (ICEM 2018) : Alexandroupoli, Greece, 3-6 September 2018 2018 / p. 2352-2358 : ill https://doi.org/10.1109/ICELMACH.2018.8506957

Cable diagnostics methods for determining degradation caused by renewable energy production
Kiitam, Ivar; **Taklaja, Paul**; **Niitsoo, Jaan**; Hyvonen, Petri 2015 IEEE 5th International Conference on Power Engineering, Energy and Electrical Drives (POWERENG) : proceedings : May 11-13, 2015, Riga, Latvia 2015 / p. 220-224 : ill

Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs
Jürimägi, Lembit; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Raik, Jaan** Microprocessors and microsystems 2020 / art. 103117, 12 p https://doi.org/10.1016/j.micpro.2020.103117 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Calculation of the diagnosibility of digital circuits without using fault models
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 159-162 : ill

Capacitor coupled voltage transformer inaccuracy effect on circuit breaker operation
Asefi, Sajjad; **Andreesen, Guido**; **Kilter, Jako**; Landsberg, Mart 2023 23rd International Scientific Conference on Electric Power Engineering (EPE) 2023 / 5 p https://doi.org/10.1109/EPE58302.2023.10149279

Causes of indefinite faults in Estonian 110 kV overhead power grid
Taklaja, Paul; **Oidram, Rein**; **Niitsoo, Jaan**; **Palu, Ivo** Oil shale 2013 / p. 225-243 : ill https://artiklid.elnet.ee/record=b2631741*est

Changing of magnetic flux density distribution in a squirrel-cage induction motor with broken rotor bars
Vaimann, Toomas; **Belahcen, Anouar**; **Kallaste, Ants** Elektronika ir elektrotechnika = Electronics and electrical engineering 2014 / p. 11-14 : ill

Combinational fault simulation in sequential circuits
Ubar, Raimund-Johannes; **Kõusaar, Jaak**; **Gorev, Maksim**; **Devadze, Sergei** 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill

Combined fault-model free cause-effect and effect-cause fault diagnosis in block-level digital networks
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** ASQED'09 : 1st Asia Symposium on Quality Electronic Design : Kuala Lumpur, Malaisia, July 15-16, 2009 2009 / p. 385-390 https://ieeexplore.ieee.org/document/5206232

Combined pseudo-exhaustive and deterministic testing of array multipliers
Oyeniran, Adeboye Stephen; **Azad, Siavoosh Payandeh**; **Ubar, Raimund-Johannes** 2018 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 21st edition, 24th-26th May, Cluj-Napoca, Romania : proceedings 2018 / 6 p. : ill https://doi.org/10.1109/AQTR.2018.8402708

Combining fault analysis technologies for ISO26262 functional safety verification
Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Hamdioui, Said; Sauer, Christian 2019 IEEE 28th Asian Test Symposium (ATS) : 10–13 December 2019, Kolkata, India : proceedings 2019 / p. 129–134 : ill https://doi.org/10.1109/ATS47505.2019.00024

Complex delay fault reasoning with sequential 7-valued algebra
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Aleksejev, Igor** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2015.7102403

Condition monitoring and fault detection for electrical machines using IOT
Raja, Hadi Ashraf; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kallaste, Ants** Proceedings of the Future Technologies Conference (FTC) 2022. Volume 2 2022 / p. 162-173 https://doi.org/10.1007/978-3-031-18458-1_12

Condition monitoring of electrical machines
Vaimann, Toomas; **Kallaste, Ants** 11th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 16-21, 2012 2012 / p. 209-212 : ill

Condition monitoring of electrical machines and its relation to industrial internet
Belahcen, Anouar; Gyftakis, Konstantinos N.; Martinez, Javier; Climente-Alarcon, Vicente; **Vaimann, Toomas** 2015 IEEE Workshop on Electrical Machines Design, Control and Diagnosis (WEMDCD) : proceedings : Castello del Valentino, Torino, Italy, 26-27 March, 2015 2015 / p. 233-241 : ill http://dx.doi.org/10.1109/WEMDCD.2015.7194535

Conditional fault collapsing in digital circuits with shared structurally synthesized BDDs [Online resource]
Jürimägi, Lembit; **Ubar, Raimund-Johannes** BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p. : ill https://doi.org/10.1109/BEC.2018.8600967

Construction of the tests of combinational circuit failures by analyzing the orthogonal disjunctive normal forms represented by the alternative graphs
Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Automation and remote control 2005 / p. 313-327 : ill http://dx.doi.org/10.1007/s10513-005-0054-9

Cost-effective concurrent hardware checkers for network on chip based system on chip = Kulutõhusad süsteemiga paralleelsed rikkemonitorid kiipvõrkudel põhinevatele kiipsüsteemidele
Hariharan, Ranganathan 2019 https://digi.lib.ttu.ee/i/?12854

Cost-efficient real-time condition monitoring and fault diagnostics system for BLDC motor using IoT and Machine learning
Raja, Hadi Ashraf; **Raval, Hardik**; **Vaimann, Toomas**; **Kallaste, Ants**; **Rassõlkin, Anton**; Belahcen, Anouar Diagnostika '22 : 2022 International Conference on Diagnostics in Electrical Engineering : conference proceedings 2022 / 4 p. https://doi.org/10.1109/Diagnostika55131.2022.9905102

Critical path tracing based simulation of transition delay faults
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

Critical path tracing based simulation of transition delay faults
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

Cross-layer dependability management in network on chip based system on chip = Kiipvõrkudel põhinevate süsteemide kihtideülene usaldatavuse haldus
Azad, Siavoosh Payandeh 2018 https://digi.lib.ttu.ee/i/?9948

Data-driven cross-layer fault management architecture for sensor networks
Vihman, Lauri; **Kruusmaa, Maarja**; **Raik, Jaan** 16th European Dependable Computing Conference : EDCC 2020 : Virtual Conference, Munich, Germany, 7-10 September 2020 : proceedings 2020 / art. 20094188, p. 33-40 https://doi.org/10.1109/EDCC51268.2020.00015

Data-driven fault-resilient cross-layer sensor network architecture = Andmepõhine tõrkekindel kihtideülene sensorvõrgu arhitektuur
Vihman, Lauri 2024 https://www.ester.ee/record=b5657135*est https://digikogu.taltech.ee/et/Item/00a93258-dc0f-4a4d-822f-099fff757224 https://doi.org/10.23658/taltech.7/2024

Deductive fault simulation on structurally synthesized BDDs
Aarna, Margit; **Ubar, Raimund-Johannes**; **Raik, Jaan** BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia 2004 / p. 11 : ill

DeepAxe : a framework for exploration of approximation and reliability trade-offs in DNN accelerators
Taheri, Mahdi; Riazati, Mohamad; **Ahmadilivani, Mohammad Hasan**; **Jenihhin, Maksim**; **Daneshtalab, Masoud**; **Raik, Jaan**; Sjödin, Mikael; Lisper, Björn arXiv.org 2023 / 8 p. : ill https://doi.org/10.48550/arXiv.2303.0822

Defect-oriented mixed-level fault simulation in digital systems
Ubar, Raimund-Johannes; **Raik, Jaan**; **Ivask, Eero**; **Brik, Marina** Facta Universitatis [Niš]. Series electronics and energetics 2002 / 1, April, p. 123-136 : ill

Defect-oriented modul-level fault diagnosis in digital circuits
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan** Proceedings of the 2011 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 13-15, 2011, Gottbus, Germany 2011 / p. 81-86

Defektide ja rikete seoste analüüs : lepingu Lep16039 aruanne [Võrguväljaanne]
Palu, Ivo; **Keel, Matti**; **Tammoja, Heiki** 2016 https://www.elektrilevi.ee/-/doc/6305157/ettevottest/defektide_rikete_aruanne.pdf

DefSim - the defective IC
Pleskacz, Witold A.; **Jutman, Artur**; **Ubar, Raimund-Johannes**; **Devadze, Sergei** DATE 2007 : Design Automation and Test in Europe : Nice, France, April 16-20, 2007 2007 / p. s96 (2 p.)

Dependability improvements of NoC-based systems = Töökindluse parandamine kiipvõrkudel põhinevates süsteemides
Niazmand, Behrad 2018 https://digi.lib.ttu.ee/i/?9879

Dependence of the carrier removal rate in 4H-SIC PN structures on irradiation temperature
Lebedev, Alexander A.; Davydovskaya, Klavdya S.; Kozlovski, Vitali V.; **Korolkov, Oleg**; **Sleptsuk, Natalja**; **Toompuu, Jana** Silicon Carbide and Related Materials 2018 : 12th European Conference on Silicon Carbide and Related Materials (ECSCRM 2018) : Selected, peer reviewed papers from the European Conference on Silicon Carbide and Related Materials (ECSCRM 2018), September 2-6, 2018,Birmingham, UK 2019 / p. 730-733 https://doi.org/10.4028/www.scientific.net/MSF.963.730 Conference proceeding at Scopus Article at Scopus

Design error diagnosis in digital circuits with stuck-at fault model
Jutman, Artur; **Ubar, Raimund-Johannes** Microelectronics reliability 2000 / 2, p. 307-320 : ill

Design issues of redundant protection and supervision system for the special purpose power converters [Electronic resource]
Vinnikov, Dmitri; **Roasto, Indrek**; **Vodovozov, Valery** International Conference on Renewable Energies and Power Quality : ICREPQ'09 : Valencia, Spain, 15th to 17th April 2009 2009 / [6] p. [CD-ROM] https://www.icrepq.com/ICREPQ%2709/356-vinnikov.pdf

Detection of induction motor broken bars in grid and frequency converter supply
Vaimann, Toomas; **Belahcen, Anouar**; Martinez, Javier; **Kilk, Aleksander** Przeglad elektrotechniczny 2014 / p. 90-94 : ill

Determined-safe faults identification : a step towards ISO26262 hardware compliant designs
Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Sartoni, Sandro; Cantoro, Riccardo; Sonza Reorda, Matteo; Hamdioui, Said; Sauer, Christian 2020 25th IEEE European Test Symposium (ETS) 2020 / 6 p. : ill https://doi.org/10.1109/ETS48528.2020.9131568

A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs
Cardoso Medeiros, Guilherme; **Gürsoy, Cemil Cem**; Fieback, Moritz; Wu, Lizhou; **Jenihhin, Maksim**; Taouil, Mottaqiallah; Hamdioui, Said 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / p. 792-797 https://doi.org/10.23919/DATE48585.2020.9116278

DfT-based external test and diagnosis of mesh-like networks on chips = Testitavusel põhinev välise testi ja diagnoosi meetod kahemõõtmelistele kiipvõrkudele
Govind, Vineeth 2009 https://digi.lib.ttu.ee/i/?454 https://www.ester.ee/record=b2539211*est

Diagnostic modeling of digital systems with low- and high-level decision diagrams
Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [1] p

Diagnostics of induction motor rotor faults using analysis of stator current
Vaimann, Toomas 6th International Symposium "Topical Problems in the Field of Electrical and Power Engineering" : Doctoral School of Energy and Geotechnology : [Kuressaare, January 12-17, 2009] 2009 / p. 13-17 : ill

DIAGNOZER : a laboratory tool for teaching research in diagnosis of electronic systems [Electronic resource]
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Jutman, Artur**; **Raik, Jaan**; Wuttke, Heinz-Dietrich 2009 IEEE International Conference on Microelectronic Systems Education MSE '09 : 25-27 July 2009, San Francisco, California : [proceedings] 2009 / p. 12-15 : ill. [CD-ROM] http://dx.doi.org/10.1109/MSE.2009.5270842

Digital twin service unit development for an EV induction motor fault detection
Rjabtšikov, Viktor; **Ibrahim, Mahmoud**; **Asad, Bilal**; **Rassõlkin, Anton**; **Vaimann, Toomas**; **Kallaste, Ants**; **Kuts, Vladimir**; Stępien, Mariusz; Krawczyk, Mateusz 2023 IEEE International Conference on Electric Machines and Drives (IEMDC) 2023 / 5 p https://doi.org/10.1109/IEMDC55163.2023.10239085

Digital Twin service unit for AC motor stator inter-turn short circuit fault detection
Rjabtšikov, Viktor; **Rassõlkin, Anton**; **Asad, Bilal**; **Vaimann, Toomas**; **Kallaste, Ants**; **Kuts, Vladimir**; **Jegorov, Sergei**; Stępien, Mariusz; Krawczyk, Mateusz 2021 28th International Workshop on Electric Drives : Improving Reliability of Electric Drives (IWED) 2021 https://doi.org/10.1109/IWED52055.2021.9376328

Distance encoding waves for identification of lighting failures
Galkin, Ilja; Suzdalenko, Alexander; **Armas, Jelena** BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 227-230 : ill

Distributed approach for parallel exact critical path tracing fault simulation
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** MIXDES 2010 : 17th International Conference "Mixed Design of Integrated Circuits and Systems" : June 24-26, 2010, Wroclaw, Poland 2010 / p. 471-476 : ill

Distributed approach for parallel exact critical path tracing fault simulation
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** International journal of microelectronics and computer science 2010 / p. 165-174 : ill

Distributed fault simulation with collaborative load balancing for VLSI circuits
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** Scalable computing : practice and experience 2011 / p. 153-163 : ill

Double phase fault collapsing with linear complexity in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Josifovska, Galina**; **Oyeniran, Adeboye Stephen** DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

Eesti soosetete leviku seosed tektooniliste riketega
Štokalenko, Mihkel; **Orru, Mall** XIX aprillikonverentsi "Eesti mere- ja maapõue uuringutest ning arukast kasutamisest" teesid 2011 / lk. 25-27 : kaart

Effect of electrode shape on medium voltage covered conductor insulation durability under electric stress
Kiitam, Ivar; **Taklaja, Paul**; **Tuttelberg, Kaur** 59th Annual International Scientific Conference on Power and Electrical Engineering : November 12, 13, 2018, Riga Technical University (RTUCON) : conference proceedings 2018 / 6 p. : ill https://doi.org/10.1109/RTUCON.2018.8659862

Effect of PM parameters variability on the operation quantities of a wind generator
Kallaste, Ants; **Belahcen, Anouar**; **Vaimann, Toomas** 2015 IEEE Workshop on Electrical Machines Design, Control and Diagnosis (WEMDCD) : proceedings : Castello del Valentino, Torino, Italy, 26-27 March, 2015 2015 / p. 242-247 : ill http://dx.doi.org/10.1109/WEMDCD.2015.7194536

Effective scalable IEEE 1687 instrumentation network for fault management
Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE design & test 2013 / p. 26-35 : ill

Efficient fault injection based on dynamic HDL slicing technique
Bagbaba, Ahmet Cagri; **Jenihhin, Maksim**; **Raik, Jaan**; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line

Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 52-53 : ill
https://doi.org/10.1109/IOLTS.2019.8854419

Efficient methodology for ISO26262 functional safety verification
Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Hamdioui, Said; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Rhodes, Greece 2019 / p. 255-256
https://doi.org/10.1109/IOLTS.2019.8854449

EFIC-ME : a fast emulation based fault injection control and monitoring enhancement
Abideen, Zain Ul; **Rashid, Muhammad Haroon** IEEE Access 2020 / p. 207705-207716
https://doi.org/10.1109/ACCESS.2020.3038198 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Elektrilevi investeeringutest ja võrgu katkestustest
Rajangu, Väino Elektriala 2015 / lk. 28

Elektrimasinate terviserikkeid aitaks ennetada tehisintellekt [Võrguväljaanne]
Kudelina, Karolina novaator.err.ee 2021 "Elektrimasinate terviserikkeid aitaks ennetada tehisintellekt"

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V : kaitsesüsteemide katsetus-, mõõte- ja seireseadmed. Osa 3, Rikkesilmuse näivtakistus = Electrical safety in low voltage distribution systems up to 1000 V a.c. and 1500 V d.c. : equipment for testing, measuring or monitoring of protective measures. Part 3, Loop impedance (IEC 61557-3:2019)
2022 https://www.ester.ee/record=b5509793*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V : kaitsesüsteemide katsetus-, mõõte- ja seireseadmed. Osa 7, Faasijärjestus = Electrical safety in low voltage distribution systems up to 1000 V a.c. and 1500 V d.c. : equipment for testing, measuring or monitoring of protective measures. Part 7, Phase sequence (IEC 61557-7:2019)
2022 https://www.ester.ee/record=b5509797*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2009 https://www.ester.ee/record=b2462029*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2009 https://www.ester.ee/record=b2462036*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2009 https://www.ester.ee/record=b2478889*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2009 https://www.ester.ee/record=b2478886*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2009 https://www.ester.ee/record=b2478887*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2010 https://www.ester.ee/record=b2594967*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitsesüsteemide katsetus-, mõõte- ja seireseadmed
Risthein, Endel 2010 https://www.ester.ee/record=b2594972*est

Enabling cross-layer reliability and functional safety assessment through ML-based compact models
Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill https://doi.org/10.1109/IOLTS50870.2020.9159750

Environment for fault simulation acceleration on FPGA
Ellervee, Peeter; **Raik, Jaan**; Tihhomirov, Valentin BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 217-220 : ill

Environment for FPGA-based fault emulation
Ellervee, Peeter; **Raik, Jaan**; **Tammemäe, Kalle**; **Ubar, Raimund-Johannes** Proceedings of the Estonian Academy of Sciences. Engineering 2006 / 3-2, p. 323-335 : ill

Environment for the analysis of functional self-test quality in digital systems
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Kruus, Helena**; **Aarna, Margit**; **Devadze, Sergei** Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill

Estimation of complex derivatives application for fault diagnosis
Baraškova, Tatjana; Pascault, D. 17th International conference on "Mathematical Modelling and Analysis" : June 6-9, 2012, Tallinn, Estonia : abstracts 2012 / p. 19

Evaluating architectural, redundancy, and implementation strategies for radiation hardening of FinFET integrated circuits
Pagliarini, Samuel Nascimento; Benites, Luis; Martins, Mayler; Rech, Paolo; Kastensmidt, Fernanda IEEE transactions on nuclear science 2021 / p. 1045-1053 https://doi.org/10.1109/TNS.2021.3070643 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Exact parallel critical path fault tracing to speed-up fault simulation in sequential circuits
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Kostin, Sergei**; **Devadze, Sergei**; **Raik, Jaan** International journal of microelectronics and computer science 2018 / p. 9–18 https://ijmcs.dmcs.pl/web/guest/vol.-9-no.-1
https://ijmcs.dmcs.pl/documents/10630/345460/IJMCS_1_2018_2.pdf

Explainability and transparency of classifiers for air-handling unit faults using explainable artificial intelligence (XAI)
Meas, Molika; Machlev, Ram; **Köse, Ahmet**; **Tepljakov, Aleksei**; **Loo, Lauri**; Levron, Yoash; **Petlenkov, Eduard**; **Belikov, Juri** Sensors 2022 / art. 6338 : ill https://doi.org/10.3390/s22176338 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Extended checkers for control part of routers in network-on-chips
Hariharan, Ranganathan; **Niazmand, Behrad**; **Hollstein, Thomas**; **Raik, Jaan**; **Jervan, Gert** MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 36-39 : ill

Facebooki katkestus mõjutas nii ettevõtete kui ka riikide toimepidevust [Võrguväljaanne]
Pärli, Merilin err.ee 2021 "Facebooki katkestus mõjutas nii ettevõtete kui ka riikide toimepidevust"

Facebooki, Instagrami ja Whatsappi tabas tohutu ülemaailmne rike [Võrguväljaanne]
ohtuleht.ee 2021 "Facebooki, Instagrami ja Whatsappi tabas tohutu ülemaailmne rike"

Fast extended test access via JTAG and FPGAs
Devadze, Sergei; **Jutman, Artur**; **Aleksejev, Igor**; **Ubar, Raimund-Johannes** International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
http://dx.doi.org/10.1109/TEST.2009.5355668

Fast identification of true critical paths in sequential circuits
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan**; **Jürimägi, Lembit** Microelectronics reliability 2018 / p. 252-261 : ill https://doi.org/10.1016/j.microrel.2017.11.027 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Fault detecting accuracy of mechanical damages in rolling bearings
Kudelina, Karolina; **Baraškova, Tatjana**; **Shirokova, Veroonika**; **Vaimann, Toomas**; **Rassõlkin, Anton** Machines 2022 / art. 86 https://doi.org/10.3390/machines10020086 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Fault detection and predictive maintenance of electrical machines : perspective chapter
Raja, Hadi Ashraf; **Kudelina, Karolina**; **Asad, Bilal**; **Vaimann, Toomas** New Trends in Electric Machines - Technology and Applications 2022 https://doi.org/10.5772/intechopen.107167

Fault diagnosis in integrated circuits with BIST
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan**; **Evartson, Teet**; **Lensen, Harri** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 604-610 : ill http://dx.doi.org/10.1109/DSD.2007.4341530

Fault diagnosis in VLSI devices
Ubar, Raimund-Johannes Proceedings of the Estonian Academy of Sciences. Engineering 1995 / 1, p. 51-67

Fault diagnosis of additional vibration in Cartesian robot
Autsou, Siarhei 21st International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of

energy and geotechnology. III" : Pärnu, Estonia, June 15-18, 2022 2022 / p. 21-22 : ill https://www.ester.ee/record=b5504019*est

Fault diagnosis system of Cartesian robot for various belt tension
Autsou, Siarhei; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kudelina, Karolina** 2022 International Conference on Diagnostics in Electrical Engineering (Diagnostika) 2022 / 4 l https://doi.org/10.1109/Diagnostika55131.2022.9905111

Fault locating in unearthed MV networks based on analysis of wave transients
Järvik, Jaan; **Panov, Valeri** The 4th International Conference Electric Power Quality and Supply Reliability : August 29...31, 2004, Pedase, Estonia : proceedings 2004 / p. 163-168

Fault management instrumentation network based on IEEE P1687 IJTAG
Shibin, Konstantin; **Jutman, Artur**; **Devadze, Sergei** European Test Symposium (ETS), 2013, Avignon, France 2013

Fault management techniques to enhance the reliability of power electronic converters : an overview
Rahimpour, Saeed; **Husev, Oleksandr**; **Vinnikov, Dmitri**; Vosoughi Kurdkandi, Naser; Tarzamni, Hadi IEEE Access 2023 / p. 13432-13446 https://doi.org/10.1109/ACCESS.2023.3242918

Fault simulation of digital systems = Digitaalsüsteemide rikete simuleerimine
Devadze, Sergei 2009 https://digi.lib.ttu.ee/i/?445 https://www.ester.ee/record=b2508727*est

Fault simulation with parallel critical path tracing for combinational circuits using structurally synthesized BDDs
Devadze, Sergei; **Raik, Jaan**; **Jutman, Artur**; **Ubar, Raimund-Johannes** 7th IEEE Latin American Test Workshop LATW'06 : Buenos Aires, Argentina, March 26th-29th, 2006 : proceedings 2006 / p. 97-102 : ill

Fault simulation with parallel exact critical path tracing in multiple core environment
Gorev, Maksim; **Ubar, Raimund-Johannes**; **Devadze, Sergei** Proceedings of the 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : 9-13 March 2015, Grenoble, France 2015 / p. 1180-1185 : ill

Fault-aware performance assessment approach for embedded networks
Malburg, Jan; **Janson, Karl**; **Raik, Jaan**; Dannemann, Frank 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 4 p. : ill
https://doi.org/10.1109/DDECS.2019.8724670

Fault-resilient NoC router with transparent resource allocation
Putkaradze, Tsotne; **Azad, Siavoosh Payandeh**; **Niazmand, Behrad**; **Raik, Jaan**; **Jervan, Gert** 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 / 8 p. : ill https://doi.org/10.1109/ReCoSoC.2017.8016161 https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=8016161

Fehler in Automaten
1989 http://www.ester.ee/record=b2015320*est

Fehlerbestimmung in kombinatorischen Scaltungen durch Lösung der Booleschen Differentialgleichungen
Ubar, Raimund-Johannes Nachrichtentechnik, Elektronik : technisch-wissenschaftlishe Zeitschrift für die gesamte elektronische Nachrichtentechnik 1978 / p. 330-334 : ill https://www.ester.ee/record=b1550811*est

Finite element analysis based technique implementation for fault diagnostic of electrical machines
Akbar, Siddique 22nd International Symposium “Topical Problems in the Field of Electrical and Power Engineering”. Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 2023 / p. 103-104
https://www.ester.ee/record=b5570906*est

First results on load model estimation using digital fault recorder measurements
Leinakse, Madis; **Sarnet, Tanel**; **Kangro, Triin**; **Kilter, Jako** 16th International Symposium "Topical Problems in the Field of Electrical and Power Engineering. Doctoral School of Energy and Geotechnology III" : Pärnu, Estonia, January 16-21, 2017 2017 / p. 101-105 : ill http://www.ester.ee/record=b4650094*est

FPGA based fault emulation of synchronous sequential circuits
Ellervee, Peeter; **Raik, Jaan**; Tihhomirov, Valentin; **Ubar, Raimund-Johannes** Proceedings [of] 22nd NORCHIP Conference : Oslo, Norway, 8-9 November 2004 2004 / p. 59-62 https://ieeexplore.ieee.org/abstract/document/1423822

FPGA-based fault emulation of synchronous sequential circuits
Ellervee, Peeter; **Raik, Jaan**; **Tammemäe, Kalle**; **Ubar, Raimund-Johannes** IET computers and digital techniques 2007 / 2, p. 70-76 : ill https://ieeexplore.ieee.org/abstract/document/1423822

A framework for combining concurrent checking and online embedded test for low-latency fault detection in NoC routers
Saltarelli, Pietro; **Niazmand, Behrad**; **Raik, Jaan**; **Govind, Vineeth**; **Hollstein, Thomas**; **Jervan, Gert**; **Hariharan, Ranganathan** NOCS '15 : International Symposium on Networks-on-Chip : Vancouver, BC, Canada, September 28-30, 2015 2015 /

[8] p. : ill http://dx.doi.org/10.1145/2786572.2788713

From online fault detection to fault management in network-on-chips : a ground-up approach
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Janson, Karl**; **Nevin, George**; **Oyeniran, Adeboye Stephen**; **Putkaradze, Tsotne**; **Apneet Kaur**; **Raik, Jaan**; **Jervan, Gert**; **Ubar, Raimund-Johannes**; **Hollstein, Thomas** Proceedings 2017 IEEE 20th International Symposium on Design and Diagnotics of Electronic Circuit & Systems(DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 48-53 : ill https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553

Handling of SETs on NoC links by exploitation of inherent redundancy in circular input buffers [Online resource]
Janson, Karl; **Pihlak, Rene**; **Azad, Siavoosh Payandeh**; **Niazmand, Behrad**; **Jervan, Gert**; **Raik, Jaan** BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill https://doi.org/10.1109/BEC.2018.8600989

Harmonic spectrum analysis of induction motor with broken rotor bar fault
Asad, Bilal; **Vaimann, Toomas**; **Kallaste, Ants**; **Belahcen, Anouar** 59th Annual International Scientific Conference on Power and Electrical Engineering : November 12, 13, 2018, Riga Technical University (RTUCON) : conference proceedings 2018 / 7 p. : ill https://doi.org/10.1109/RTUCON.2018.8659842

Health management for self-aware SoCs based on IEEE 1687 infrastructure
Shibin, Konstantin; **Devadze, Sergei**; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill https://doi.org/10.1109/MDAT.2017.2750902

Hierarchical identification of NBTI-critical gates in nanoscale logic
Kostin, Sergei; **Raik, Jaan**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Hierarchical identification of untestable faults in sequential circuits
Raik, Jaan; **Ubar, Raimund-Johannes**; **Krivenko, Anna**; **Kruus, Margus** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill http://dx.doi.org/10.1109/DSD.2007.4341539

High level fault modeling in digital systems
Ubar, Raimund-Johannes; **Aarna, Margit**; **Brik, Marina**; **Raik, Jaan** Synergies between Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 486-491

High-frequency current sensor for power network on-line mea[s]urements
Kütt, Lauri; **Järvik, Jaan**; **Vaimann, Toomas**; Shafiq, Muhammad; Lehtonen, Matti; **Kilter, Jako** Proceedings of the 13th International Scientific Conference Electric Power Engineering 2012 : EPE 2012 : Brno. Vol. 1 2012 / p. 367-371 : ill https://www.researchgate.net/publication/262674502_High-Frequency_Current_Sensor_for_Power_Network_On-line_Measurements

High-level decision diagram based fault models for targeting FSMs
Raik, Jaan; **Ubar, Raimund-Johannes**; **Viilukas, Taavi** 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 353-358 : ill http://dx.doi.org/10.1109/DSD.2006.60

High-level design error diagnosis using backtrace on decision diagrams
Raik, Jaan; **Repinski, Urmas**; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Tšepurov, Anton** 28th Norchip Conference : Tampere, Finland, 15-16 November 2010 : conference program and papers 2010 / [4] p. : ill http://dx.doi.org/10.1109/NORCHIP.2010.5669486

High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test
Oyeniran, Adeboye Stephen; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes** 2022 IEEE Computer Society Annual Symposium on VLSI (ISVLSI) : Nicosia, Cyprus : 04-06 July 2022 2022 / p. 32-37 https://doi.org/10.1109/ISVLSI54635.2022.00019

High-level functional test generation for microprocessor modules
Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes** Proceedings of 26th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2019 : Rzeszów, Poland, June 27 - 29, 2019 2019 / p. 356-361 : ill https://doi.org/10.23919/MIXDES.2019.8787131

High-level modeling and testing of multiple control faults in digital systems
Jasnetski, Artjom; **Oyeniran, Adeboye Stephen**; **Tšertov, Anton**; Schölzel, Mario; **Ubar, Raimund-Johannes** Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill http://dx.doi.org/10.1109/DDECS.2016.7482445

High-level test generation for processing elements in many-core systems
Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes**; **Azad, Siavoosh Payandeh**; **Raik, Jaan** 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 /

8 p. : ill http://dx.doi.org/10.1109/ReCoSoC.2017.8016156

Holistic approach for Fault-Tolerant Network-on-Chip based many-core systems [Online resource]
Azad, Siavoosh Payandeh; **Niazmand, Behrad**; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** arXiv.org 2016 / [8] p. : ill

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks
Orasson, Elmet 2007 https://www.ester.ee/record=b2305436*est

Hybrid FEA-simulink modelling of permanent magnet assisted synchronous reluctance motor with unbalanced magnet flux
Pando-Acedo, Jaime; **Rassõlkin, Anton**; Lehikoinen, Antti; **Vaimann, Toomas**; **Kallaste, Ants**; Romero-Cadaval, Enrique; **Belahcen, Anouar** 2019 IEEE 12th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED), 27-30 Aug. 2019, Toulouse, France : proceedings 2019 / p. : 174-180 : ill https://doi.org/10.1109/DEMPED.2019.8864925

Identification and location of PD defects in medium voltage underground power cables using high frequency current transformer
Shafiq, Muhammad; **Kiitam, Ivar**; **Taklaja, Paul**; **Kütt, Lauri**; Kauhaniemi, Kimmo; **Palu, Ivo** IEEE Access 2019 / art. 8771171, p. 103608 - 103618 : ill https://doi.org/10.1109/ACCESS.2019.2930704 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Impact of faults and different operating conditions on current parameters in case of broken rotor bars
Kudelina, Karolina 21st International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Pärnu, Estonia, June 15-18, 2022 2022 / p. 41-42 : ill https://www.ester.ee/record=b5504019*est

Implementation-independent functional test generation for RISC microprocessors
Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes**; **Jenihhin, Maksim**; **Raik, Jaan** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill https://doi.org/10.1109/VLSI-SoC.2019.8920323

Implementation-independent test generation for a large class of faults in RISC processor modules
Jenihhin, Maksim; **Oyeniran, Adeboye Stephen**; **Raik, Jaan**; **Ubar, Raimund-Johannes** 24th Euromicro Conference on Digital System Design (DSD) 2021 https://doi.org/10.1109/DSD53832.2021.00090

Improved fault emulation for synchronous sequential circuits
Raik, Jaan; **Ellervee, Peeter**; **Tihhomirov, Valentin**; **Ubar, Raimund-Johannes** Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 72-78 : ill

Improving the confidence level in functional safety simulation tools for ISO 26262
Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill https://dvcon-proceedings.org/document/improving-the-confidence-level-in-functional-safety-simulation-tools-for-iso-26262/ https://zenodo.org/record/3361607#.Y0PHFnZByHs

Insulation durability and measurement of partial discharge = Isolatsiooni vastupidavus ja osalahenduste mõõtmine
Kiitam, Ivar 2021 https://www.ester.ee/record=b5473274*est https://digikogu.taltech.ee/et/Item/401e6d0b-f51d-488f-b0d6-2e2bdb8f9496 https://doi.org/10.23658/taltech.62/2021

Integrated modelling, fault management, verification and reliable design environment for cyber-physical systems
Raik, Jaan; Rauwerda, Gerard; Zhao, Yong; **Shibin, Konstantin** MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 74

Investigating the progression of insulation degradation in power cable based on partial discharge measurements
Hassan, Waqar; **Shafiq, Muhammad**; Hussain, Ghulam Amjad; **Choudhary, Maninder**; **Palu, Ivo** Electric power systems research 2023 / art. 109452 https://doi.org/10.1016/j.epsr.2023.109452

IoT based tools and methods for electrical machine diagnostics = Asjade interneti põhised tööriistad ja meetodid elektrimasinate diagnostikaks
Raja, Hadi Ashraf 2023 https://doi.org/10.23658/taltech.20/2023 https://digikogu.taltech.ee/et/Item/3015334f-c32b-43ae-ba2d-bfcda536aba5 https://www.ester.ee/record=b5558656*est

Kordsete rikete diagnostika järjestiklülitustes
Puulinn, S.; **Ubar, Raimund-Johannes** XXIX vabariiklik üliõpilaste teaduslik- tehniline konverents 30. märtsist - 1. aprillini 1977 : ettekannete teesid 1977 / lk. 43 https://www.ester.ee/record=b2449987*est

Kui pikk peab olema elektrikatkestus

Valdna, Vello Tallinna Tehnikaülikooli aastaraamat 2003 2004 / lk. 169-170

Kui pikk peab olema elektrikatkestus : [poliitikud peavad väärtustama reaalharidust, inseneriкoolitust ja tehnikateadusi]
Valdna, Vello Postimees 2003 / 23. sept., lk. 13 https://arvamus.postimees.ee/2049577/kui-pikk-peab-olema-elektrikatkestus

Kuidas teha peedist pesumasinale trumlit? Auvere elektrijaam neelab veel miljoneid ega hakka niipea normaalselt tööle!
Niitra, Nils ohtuleht.ee 2023 / Lk. 4-5 Kuidas teha peedist pesumasinale trumlit? Auvere elektrijaam neelab veel miljoneid ega hakka niipea normaalselt tööle!

Logic simulation and fault collapsing with shared structurally synthesized BDDs
Mironov, Dmitri; **Ubar, Raimund-Johannes**; **Raik, Jaan** 2014 19th IEEE European Test Symposium (ETS) : May 26th-30th, 2014, Paderborn, Germany : proceedings 2014 / [2] p. : ill

Logic-based implementation of fault-tolerant routing in 3D Network-on-Chips
Niazmand, Behrad; **Azad, Siavoosh Payandeh**; Flich, Jose; **Raik, Jaan**; **Jervan, Gert**; **Hollstein, Thomas** 2016 Tenth IEEE/ACM International Symposium on Networks-on-Chip (NOCS) : Nara, Japan, 31 August - 2 September 2016 2016 / [8] p. : ill https://doi.org/10.1109/NOCS.2016.7579317

Machine learning clustering techniques for selective mitigation of critical design features
Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 7 p. : ill https://doi.org/10.1109/IOLTS50870.2020.9159751

Machine learning to tackle the challenges of transient and soft errors in complex circuits
Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Greece 2019 / p. 7-14 : ill https://doi.org/10.1109/IOLTS.2019.8854423

Macro level defect-oriented diagnosability of digital circuits
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 149-152 : ill

Magnetic equivalent circuit and Lagrange interpolation function modeling of induction machines under broken bar faults
Hemeida, Ahmed; Billah, Md Masum; **Kudelina, Karolina**; **Asad, Bilal**; **Naseer, Muhammad Usman**; Guo, Baocheng; Martin, Floran; Rasilo, Paavo; Belahcen, Anouar IEEE transactions on magnetics 2023 https://doi.org/10.1109/TMAG.2023.3306207

Main bird excrement contamination type causing insulator flashovers in 110 kV overhead power lines in Estonia
Taklaja, Paul; **Oidram, Rein**; **Niitsoo, Jaan**; **Palu, Ivo** Oil shale 2013 / p. 211-224 : ill

Main gear-faults in industrial hitara
Autsou, Siarhei 20th International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Tallinn, Estonia, September 8-10, 2021 2022 / p. 17-18 : ill https://www.ester.ee/record=b5457278*est

Marginal PCB assembly defect detection on DDR3/4 memory bus
Odintsov, Sergei; **Jutman, Artur**; **Devadze, Sergei** 2017 IEEE International Test Conference (ITC 2017) : Forth Worth, Texas, USA, 31 October - 2 November 2017 2017 / p. 238-247 : ill https://doi.org/10.1109/TEST.2017.8242070

Mathematical modelling of three phase squirrel cage induction motor and related signal processing for fault diagnostics = Kolmefaasilise lühisrootoriga asünkroonmootori matemaatiline modelleerimine ning lähtuv rikkediagnostiline signaalitöötlus
Asad, Bilal 2021 https://digikogu.taltech.ee/et/Item/8b5869c8-de30-4380-a0c6-8a6a2d6b6ff3 https://www.ester.ee/record=b5452432*est https://doi.org/10.23658/taltech.40/2021

Me peame rääkima Facebookist
Kivi, Krister Postimees 2021 / Lk. 17 https://www.ester.ee/record=b1072778*est

Metallitööstus pani tehisintellekti seadmetest rikkeid otsima [Võrguväljaanne]
toostusuudised.ee 2022 / Lk. 14 Metallitööstus pani tehisintellekti seadmetest rikkeid otsima

Methods for improving the accuracy and efficiency of fault simulation in digital systems = Meetodid digitaalsüsteemide rikete simuleerimise täpsuse ja efektiivsuse tõstmiseks
Kõusaar, Jaak 2019 https://digi.lib.ttu.ee/i/?11667

Methods of condition monitoring and fault detection for electrical machines
Kudelina, Karolina; **Asad, Bilal**; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kallaste, Ants**; Khang, Huynh Van Energies 2021 / art.

7459, 20 p. : ill https://doi.org/10.3390/en14227459 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Miks Facebook ei tööta? Põhjuseks võib olla ebaõnnestunud tarkvarauuendus [Võrguväljaanne]
Veedla, Alice delfi.ee 2021 "Miks Facebook ei tööta? Põhjuseks võib olla ebaõnnestunud tarkvarauuendus "

Minimization of the high-level fault model for microprocessor control parts [Online resource]
Ubar, Raimund-Johannes; **Oyeniran, Adeboye Stephen**; **Medaiyese, Olusiji** BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill https://doi.org/10.1109/BEC.2018.8600980

Missugused varutoiteallikad valida, et elada üle elektrikatkestused
Thalfeldt, Martin; **Rosin, Argo** maakodu.delfi.ee 2023 Missugused varutoiteallikad valida, et elada üle elektrikatkestused

Model verification for analysis of wind power impact to transient stability in isolated power system using combined relay protection and dynamics modelling approach
Maripuu, Rain; **Tsernobrovkin, Oleg**; **Palu, Ivo**; **Kilter, Jako** PQ2012 : 8th International Conference : 2012 Electric Power Quality and Supply Reliability : June 11-13, 2012, Tartu, Estonia : conference proceedings 2012 / p. 169-174 : ill https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=6256222

Modeling sequential circuits with shared structurally synthesized BDDs
Ubar, Raimund-Johannes; **Marenkov, Mihhail**; **Mironov, Dmitri**; **Viies, Vladimir** Proceedings of 2014 9th International Design & Test Symposium (IDT) : Sheraton Club des Pins Hotel, Algiers, Algeria, December 16-18, 2014 2014 / p. 130-135 : ill

Modified winding function-based model of squirrel cage induction motor for fault diagnostics
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; **Rassõlkin, Anton**; **Iqbal, Muhammad Naveed** IET electric power applications 2020 / p. 1722-1734 https://doi.org/10.1049/iet-epa.2019.1002 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Mootoririkkega uurimislaev Salme ootab tormivarjus ilma paranemist [Võrguväljaanne]
postimees.ee 2021 "Mootoririkkega uurimislaev Salme ootab tormivarjus ilma paranemist"

Multi-level fault simulation of digital systems on decision diagrams
Ubar, Raimund-Johannes; **Raik, Jaan**; **Ivask, Eero**; **Brik, Marina** The First IEEE International Workshop on Electronic Design, Test and Applications : DELTA 2002, 29-31 January 2002, Christchurch, New Zealand : proceedings 2002 / p. 86-91 : ill

Multi-level test generation and fault diagnosis in digital systems
Ubar, Raimund-Johannes 1992

Multi-loop model reference adaptive control of fractional-order PID control systems
Alagoz, Baris Baykant; **Tepljakov, Aleksei**; **Petlenkov, Eduard**; Yeroglu, Celaleddin 2017 40th International Conference on Telecommunications and Signal Processing TSP : July 5-7, 2017, Barcelona, Spain 2017 / p. 702-705 : ill https://doi.org/10.1109/TSP.2017.8076078

Multiple control fault testing in digital systems with high-level decision diagrams
Ubar, Raimund-Johannes; **Oyeniran, Adeboye Stephen** 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill http://dx.doi.org/10.1109/AQTR.2016.7501287

Multiple fault testing in systems-on-chip with high-level decision diagrams
Ubar, Raimund-Johannes; **Oyeniran, Adeboye Stephen**; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill http://dx.doi.org/10.1109/IDT.2015.7396738

Multiple stuck-at-fault detection theorem
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia 2012 / p. 236-241 : ill

Naine, kes muudab maailma: noor teadlane loob süsteemi, mis ennetab elektrimasinate rikkeid [Võrguväljaanne]
Keba, Triinu delfi.ee 2022 Naine, kes muudab maailma: noor teadlane loob süsteemi, mis ennetab elektrimasinate rikkeid

Necessity for implementation of inverse problem theory in electric machine fault diagnosis
Vaimann, Toomas; **Belahcen, Anouar**; **Kallaste, Ants** SDEMPED 2015 : 10th IEEE International Symposium on Diagnostics for Electric Machines, Power Electronics and Drives : Guarda, Portugal, September 1-4, 2015 : proceedings 2015 / p. 380-385 : ill http://dx.doi.org/10.1109/DEMPED.2015.7303718

New categories of Safe Faults in a processor-based Embedded System
Gürsoy, Cemil Cem; **Jenihhin, Maksim**; **Oyeniran, Adeboye Stephen**; Piumatti, Davide; **Raik, Jaan**; Sonza Reorda, Matteo;

Ubar, Raimund-Johannes 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 4 p. : ill https://doi.org/10.1109/DDECS.2019.8724642

New technique for hierarchical identification of untestable faults in sequential circuits
Krivenko, Anna; **Ubar, Raimund-Johannes**; **Raik, Jaan**; **Kruus, Margus** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / lk. 155-158 : ill

NoCDepend : a flexible and scalable dependability technique for 3D networks-on-chip
Hollstein, Thomas; **Azad, Siavoosh Payandeh**; **Kogge, Thilo**; Ying, Haoyuan; Hofmann, Klaus 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 75-78 : ill http://dx.doi.org/10.1109/DDECS.2015.30

Non-intrusive defects identification for the high voltage instrument transformers
Asefi, Sajjad; **Kilter, Jako**; **Landsberg, Mart** 2023 IEEE 17th International Conference on Compatibility, Power Electronics and Power Engineering (CPE-POWERENG) 2023 / 5 p https://doi.org/10.1109/CPE-POWERENG58103.2023.10227493

Novel approaches to electrical machine fault diagnosis
Vaimann, Toomas; Antonino-Daviu, Jose Alfonso; **Rassõlkin, Anton** Energies 2023 / art. 5641 https://doi.org/10.3390/en16155641

A novel random approach to diagnostic test generation
Osimiry, Emmanuel Ovie; **Ubar, Raimund-Johannes**; **Kostin, Sergei**; **Raik, Jaan** 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill https://doi.org/10.1109/NORCHIP.2016.7792915

Numerical study on the structural behavior of intact and damaged box beams under four-point bending load
Putranto, Teguh; **Kõrgesaar, Mihkel** Developments in the Collision and Grounding of Ships and Offshore Structures : Proceedings of the 8th International Conference on Collision and Grounding of Ships and Offshore Structures (ICCGS 2019), 21-23 October, 2019, Lisbon, Portugal 2019 / p. 139−143 https://www.taylorfrancis.com/books/e/9781003002420/chapters/10.1201/9781003002420-17

Observer-based residual generation for nonlinear discrete-time systems
Kaldmäe, Arvo; **Kotta, Ülle** Proceedings of the Estonian Academy of Sciences 2018 / p. 325-336 http://www.kirj.ee/public/proceedings_pdf/2018/issue_4/proc-2018-4-325-336.pdf https://doi.org/10.3176/proc.2018.4.01 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Off-line testing of crosstalk induced glitch faults in NoC Interconnects
Bengtsson, Tomas; Kumar, Shashi; **Jutman, Artur**; **Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 221-225 : ill http://dx.doi.org/10.1109/NORCHP.2006.329215

On coverage of timing related faults at board level
Jutman, Artur; **Aleksejev, Igor**; **Devadze, Sergei** 2016 21st IEEE European Test Symposium (ETS) : May 23rd-26th 2016, Amsterdam, The Netherlands : proceedings 2016 / [2] p. : ill https://doi.org/10.1109/ETS.2016.7519295

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks
Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill https://doi.org/10.1109/VLSI-SoC.2019.8920313

On the estimation of complex circuits functional failure rate by machine learning techniques
Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 49th Annual IEEE/IFIP International Conference on Dependable Systems and Networks - DSN 2019 : Supplemental Volume : proceedings 2019 / p. 35-41 : ill https://doi.org/10.1109/DSN-S.2019.00021

On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs
Shibin, Konstantin; **Devadze, Sergei**; **Jutman, Artur** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill https://doi.org/10.1109/LATW.2016.7483342

Operation of Single-Chip MOSFET and IGBT Devices after failure due to repetitive avalanche [Electronic resource]
Blinov, Andrei; Norrga, Staffan; Tibola, Gabriel EPE'15 ECCE Europe : 8-10 September 2015, Geneva, Switzerland : 17th European Conference on Power Electronics and Applications 2015 / p. 1-9 : ill. [USB] http://dx.doi.org/10.1109/EPE.2015.7309190

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems
Jutman, Artur; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 5th European Workshop on Microelectronics Education, held in Lausanne, Switzerland, April 15-16, 2004 2004 / p. 253-258 : ill https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems
Jutman, Artur; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich 5th European Workshop on Microelectronics Education - EWME 2004, Lausanne, 2004 2004 / p. 173-176 https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Parallel critical path tracing fault simulation in sequential circuits
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Kostin, Sergei**; **Devadze, Sergei**; **Raik, Jaan** Proceedings of 25th International Conference MIXED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS : MIXDES 2018 : Gdynia, Poland, June 21–23, 2018 2018 / p. 305-310 : ill https://doi.org/10.23919/MIXDES.2018.8436880

Parallel exact critical path tracing fault simulation with reduced memory requirements
Devadze, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan**; **Jutman, Artur** 4th International Conference on Design and Technology of Integrated Systems in Nanoscal Era : DTIS'09 : Cairo, Egypt, April 6-9, 2009 2009 / p. 155-160 : ill https://ieeexplore.ieee.org/document/4938046

Parallel fault analysis on structurally synthesized BDDs
Devadze, Sergei; **Ubar, Raimund-Johannes** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 47-50 : ill

Parallel fault simulation in digital circuits
Aarna, Margit; **Raik, Jaan**; **Ubar, Raimund-Johannes** Scientific proceedings of Riga Technical University. 7. serija, Telecommunications and electronics 2001 / p. 91-94 : ill

Parallel fault simulation in digital circuits
Aarna, Margit; **Raik, Jaan**; **Ubar, Raimund-Johannes** Proc. of 42nd International Scientific Conference of Riga Technical University 2001 / p. 91-94

Performance evaluation of additive manufacturing based test samples for studies of defects in electrical insulation
Shafiq, Muhammad; **Taklaja, Paul**; **Kiitam, Ivar**; **Tiismus, Hans**; **Palu, Ivo**; **Kütt, Lauri** 2021 International Conference on Electrical, Computer and Energy Technologies (ICECET) 2021 / 6 l https://doi.org/10.1109/ICECET52533.2021.9698476

Power quality issues in dispersed generation and smart grids
Vaimann, Toomas; **Niitsoo, Jaan**; **Kivipõld, Tanel**; **Lehtla, Tõnu** Elektronika ir elektrotechnika = Electronics and electrical engineering 2012 / p. 23-26 : ill https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=573c03a0753bcfce3929ba739ff032b16882acf5

Preliminary analysis of bearing current faults for predictive maintenance
Kudelina, Karolina 22nd International Symposium “Topical Problems in the Field of Electrical and Power Engineering”. Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 2023 / p. 35-36 : ill https://www.ester.ee/record=b5570906*est

Preliminary analysis of global parameters of induction machine for fault prediction in rotor bars
Kudelina, Karolina; **Raja, Hadi Ashraf**; **Autsou, Siarhei**; **Asad, Bilal**; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kallaste, Ants** 2022 IEEE 20th International Power Electronics and Motion Control Conference (PEMC) : Brasov, Romania, 25-28 Sept. 2022 : proceedings 2022 / p. 243-248 : ill https://doi.org/10.1109/PEMC51159.2022.9962922

Preliminary analysis of mechanical bearing faults for predictive maintenance of electrical machines
Kudelina, Karolina; **Raja, Hadi Ashraf**; **Autsou, Siarhei**; **Naseer, Muhammad Usman**; **Vaimann, Toomas**; **Kallaste, Ants**; Pomamacki, Raimondas; Hyunh, Van Khang 2023 IEEE 14th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED) 2023 / p. 430-435 https://doi.org/10.1109/SDEMPED54949.2023.10271451

Register-transfer level deductive fault simulation using decision diagrams
Reinsalu, Uljana; **Raik, Jaan**; **Ubar, Raimund-Johannes** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 193-196 : ill

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG
Palermo, N.; **Tihhomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim**; **Raik, Jaan**; **Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill http://dx.doi.org/10.1109/LATW.2015.7102405

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687
Jutman, Artur; **Shibin, Konstantin**; **Devadze, Sergei** IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill https://doi.org/10.1109/AUTEST.2016.7589605

Riigijuhid, kuhu jääb elektritootmise strateegia?
Rajangu, Väino Eesti Päevaleht 2023 / Lk. 3 https://dea.digar.ee/article/eestipaevaleht/2023/01/10/3.5 Riigijuhid, kuhu jääb elektritootmise strateegia?

Rikkevoolukaitse
Teemets, Raivo 2004 https://www.ester.ee/record=b1961658*est

Rikkevoolukaitse
Teemets, Raivo Ehitaja 1996 / 8, lk. 69-70: ill

Rikkevoolukaitse lülitite paigaldamine
Teemets, Raivo Ehitaja 1996 / 9, lk. 73-74: ill

Rotor fault diagnostic of inverter fed induction motor using frequency analysis
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; **Rassõlkin, Anton** 2019 IEEE 12th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED), 27-30 Aug. 2019, Toulouse, France : proceedings 2019 / p. 127-133 : ill https://doi.org/10.1109/DEMPED.2019.8864903

110 kV õhuliinide isolatsiooni töökindluse analüüs ja töökindluse tõstmise meetodid = The study of 110 kV power grid reliability and the measures to decrease insulation failure
Taklaja, Paul 2012 http://www.ester.ee/record=b2857612*est

Scalable algorithm for structural fault collapsing in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

Self-diagnosis in digital systems = Isediagnoosivad digitaalsüsteemid
Kostin, Sergei 2012 https://www.ester.ee/record=b2757857*est

7-valued algebra for transition delay fault analysis
Kõusaar, Jaak; **Ubar, Raimund-Johannes** BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Raik, Jaan** 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill http://dx.doi.org/10.1109/NORCHIP.2015.7364406

Short-circuit protection circuits for silicon-carbide power transistors
Sadik, Diane-Perle; Colmenares, Juan; Tolstoy, Georg; **Rabkowski, Jacek** IEEE transactions on industrial electronics 2016 / p. 1995-2004 : ill https://doi.org/10.1109/TIE.2015.2506628

Signal processing and machine learning techniques for predictive maintenance of rotor bars in induction machine
Kudelina, Karolina; **Raja, Hadi Ashraf**; **Rjabtšikov, Viktor**; **Naseer, Muhammad Usman**; **Vaimann, Toomas**; **Kallaste, Ants** 2023 International Conference on Electrical Drives and Power Electronics (EDPE) 2023 / 7 p
https://doi.org/10.1109/EDPE58625.2023.10274030

Simple relationship between the breakdown voltage, concentration and junction depth pn diffused junctions
Rang, Toomas Physica status solidi. A, Applied research 1982 / p. K117-K119 : tab., joon https://www.ester.ee/record=b1562026*est

Software-level TMR approach for on-board data processing in space applications
Janson, Karl; Treudler, Carl Johann; **Hollstein, Thomas**; **Raik, Jaan**; **Jenihhin, Maksim**; Fey, Goerschwin 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 147-152 : ill https://doi.org/10.1109/DDECS.2018.00033

Sonda tektooniline rike Põhja-Kiviõli karjääris
Sõstra, Ülo; **Vaher, Rein** XV aprillikonverentsi "Geoloogilise kaardistamise poolsajand" teesid : [30. märts 2007, Tallinn] 2007 / lk. 37-39 : ill

Spectrum analysis additional vibrations of Cartesian robot by different control modes
Autsou, Siarhei; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kudelina, Karolina** 2022 18th Biennial Baltic Electronics Conference (BEC) 2022 / 5 l. https://doi.org/10.1109/BEC56180.2022.9935595

Stator voltage analysis of frequency converter fed induction generator with broken rotor bars
Vaimann, Toomas; **Belahcen, Anouar**; Martinez, Javier; **Kilk, Aleksander** 13th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 14-19, 2013 2013 / p. 249-251 : ill

Studing the impact of gearbox faults on the operations of the cartesian robot
Autsou, Siarhei 22nd International Symposium “Topical Problems in the Field of Electrical and Power Engineering”. Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 2023 / p. 17-18 : ill https://www.ester.ee/record=b5570906*est

Study of overvoltages upon single-phase ground fault initialisation and arcing processes on MV networks with isolated neutral
Kütt, Lauri; **Järvik, Jaan**; **Sepping, Eino** The 4th International Conference Electric Power Quality and Supply Reliability : August 29...31, 2004, Pedase, Estonia : proceedings 2004 / p. 139-143 : ill

Suppression of voltage flicker by saturable reactor operating under forced magnetization [Electronic resource]
Bolgov, Viktor; **Järvik, Jaan** EUROCON 2007 : the International Conference on Computer as a Tool : September 9-12, 2007, Warsaw, Poland : proceedings 2007 / p. 1417-1422 : ill. [CD-ROM] https://ieeexplore.ieee.org/document/4400513

A survey of broken rotor bar fault diagnostic methods of induction motor
Asad, Bilal; **Vaimann, Toomas**; **Rassõlkin, Anton**; **Kallaste, Ants**; **Belahcen, Anouar** Scientific Journal of Riga Technical University. Electrical, control and communication engineering 2018 / p. 117–124 : ill https://doi.org/10.2478/ecce-2018-0014

A survey on UAV computing platforms : a hardware reliability perspective
Ahmed, Foisal; **Jenihhin, Maksim** Sensors 2022 / art. 6286 https://doi.org/10.3390/s22166286 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]

A synthetic, hierarchical approach for modelling and managing complex systems' quality and reliability = Sünteetiline, hierarhiline lähenemine keerukate süsteemide kvaliteedi ja töökindluse modelleerimiseks ja haldamiseks
Balakrishnan, Aneesh 2022 https://doi.org/10.23658/taltech.11/2022 https://digikogu.taltech.ee/et/Item/a594d3ec-0e6b-4a78-819a-fe1f47992612

Teaching diagnostic modeling of digital systems with decision diagrams [Electronic resource]
Ubar, Raimund-Johannes; **Raik, Jaan**; Mironov, Dmitri; **Evartson, Teet**; **Orasson, Elmet**; **Aarna, Margit**; Wuttke, Heinz-Dietrich Proceedings of 12th IASTED International Conference on Computers and Advanced Technology in Education - CATE 2009 : St.Thomas, US, November 22-24, 2009 2009 / p. 1-6. [CD-ROM]

Teaching digital system test
Oyeniran, Adeboye Stephen; **Ubar, Raimund-Johannes**; **Kruus, Margus** The 27th EAEEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p

Techniques for robust routing, communication and computation in multiprocessor systems = Robustse marsruutimise, side ja arvutuse tehnikad mitmeprotsessorilistes süsteemides
Janson, Karl 2021 https://www.ester.ee/record=b5396084*est https://digikogu.taltech.ee/et/Item/c9091d5c-dcd8-4b21-95a7-84ead85241e6 https://doi.org/10.23658/taltech.3/2021

Tehisintellekt pandi metalliettevõttes rikkeid otsima, et vähendada tootmiskulusid [Võrguväljaanne]
am.ee 2022 Tehisintellekt pandi metalliettevõttes rikkeid otsima, et vähendada tootmiskulusid

Test configurations for diagnosing faulty links in NoC switches
Raik, Jaan; **Ubar, Raimund-Johannes**; **Govind, Vineeth** Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 33-37 : ill

Test configurations for diagnosing faulty links in NoC switches
Raik, Jaan; **Ubar, Raimund-Johannes**; **Govind, Vineeth** 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 29-34 : ill http://dx.doi.org/10.1109/ETS.2007.41

The FEM based modeling and corresponding test rig preparation for broken rotor bars analysis
Asad, Bilal; **Eensalu, Lauri**; **Vaimann, Toomas**; **Kallaste, Ants**; **Rassõlkin, Anton**; Belahcen, Anouar 2019 IEEE 60th International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON), 7-9 October 2019 : conference proceedings 2019 / 9 p. : ill https://doi.org/10.1109/RTUCON48111.2019.8982350

The investigation of the Therac-25 accidents
Zdanov, Vassili A & A 2007 / 6, lk. 20-32 : ill https://artiklid.elnet.ee/record=b1021179*est

The study about indefinite fault causes in Estonian 110 kV power grid
Taklaja, Paul; **Oidram, Rein** PQ2010 : 7th International Conference "2010 Electric Power Quality and Supply Reliability" : June 16-18, 2010, Kuressaare, Estonia 2010 / p. 177-182 : ill

3D parallel fault simulation
Gorev, Maksim; **Ubar, Raimund-Johannes** Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 39-42 : ill

3D permeance model of induction machines taking into account saturation effects and its connection with stator current and shaft speed spectra
Martinez, Javier; **Belahcen, Anouar**; Arkkio, Antero IET electric power applications 2015 / p. 20-29 : ill http://dx.doi.org/10.1049/iet-epa.2014.0013

Transient modeling and recovery of non-stationary fault signature for condition monitoring of induction motors
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; **Rassõlkin, Anton**; Ghahfarokhi, Payam Shams; **Kudelina, Karolina** Applied sciences 2021 / 17 p. : ill https://doi.org/10.3390/app11062806 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Transient modeling and recovery of non-stationary fault signature for condition monitoring of induction motors
Asad, Bilal; **Vaimann, Toomas**; **Belahcen, Anouar**; **Kallaste, Ants**; **Rassõlkin, Anton**; **Ghahfarokhi, Payam Shams** Advances in machine fault diagnosis 2022 / p. 43-59 https://doi.org/10.3390/app11062806

Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra
Kõusaar, Jaak; **Ubar, Raimund-Johannes**; **Devadze, Sergei**; **Raik, Jaan** Microprocessors and microsystems 2015 / p. 1130-1138 : ill http://dx.doi.org/10.1016/j.micpro.2015.05.003

Troubleshooting and debugging functions
Ruban, Olga; **Laugis, Juhan** 5th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology : Kuressaare, January 14-19, 2008 2008 / p. 216-221 : ill

Troubleshooting process analysis and development of application for decision making enhancement
Mahmood, Kashif; **Ševtšenko, Eduard**; **Karaulova, Tatjana**; **Branten, Eva**; Maleki, Meysam 26th DAAAM International Symposium on Intelligent Manufacturing and Automation 2015 (DAAAM 2015) : Zadar, Croatia, 21-24 October 2015. Volume 1 2016 / p. 0663-0671 : ill http://dx.doi.org/10.2507/26th.daaam.proceedings.090

A 2D FEM model for transient and fault analysis of induction machines
Martinez, Javier; **Belahcen, Anouar**; Arkkio, Antero Przeglad elektrotechniczny = Electrical review 2012 / p. 157-160 : ill http://pe.org.pl/articles/2012/7b/41.pdf

Ultra fast parallel fault analysis on structurally synthesized BDDs
Ubar, Raimund-Johannes; **Devadze, Sergei**; **Raik, Jaan**; **Jutman, Artur** 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 131-136 : ill http://dx.doi.org/10.1109/ETS.2007.43

Understanding MPSoCs : exploiting memory microarchitectural vulnerabilities of high performance NoC-based MPSoCs
Sepulveda, Johanna; **Azad, Siavoosh Payandeh**; **Niazmand, Behrad**; **Jervan, Gert** SAMOS '18 : Proceedings of the 18th International Conference on Embedded Computer Systems: Architectures, Modeling, and Simulation, Pythagorion, Greece, July 15-19, 2018 2018 / p. 162-166 https://doi.org/10.1145/3229631.3239367 Conference proceedings at Scopus Article at Scopus Article at WOS

Untestable fault identification in sequential circuits using model-checking
Raik, Jaan; Fujiwara, Hideo; **Ubar, Raimund-Johannes**; **Krivenko, Anna** Proceedings of the 17th Asian Test Symposium ATS 2008 : November 24-27, 2008, Sapporo, Japan 2008 / p. 21-26 : ill http://dx.doi.org/10.1109/ATS.2008.22

Untestable fault identification in sequential circuits using model-checking
Raik, Jaan; Fujiwara, Hideo; **Ubar, Raimund-Johannes**; **Krivenko, Anna** 2002-2011 : 20th Anniversary compendium of papers from Asian Test Symposium 2011 / p. 257-262 : ill https://ieeexplore.ieee.org/document/4711554

Uuenduslik metoodika aitab võidelda elektrisüsteemi riketega
Andreesen, Guido novaator.err.ee 2024 Uuenduslik metoodika aitab võidelda elektrisüsteemi riketega

Uuendusliku metoodikaga elektrisüsteemi rikete vastu
Andreesen, Guido TööstusEST 2024 / lk. 67 : portr https://www.ester.ee/record=b4481084*est

Veepuhastusjaama juurdevoolukanalis toimunud avarii põhjustest
Jaaniso, Valdo Ehitaja 1998 / lk. 86-87, 89: ill https://www.ester.ee/record=b1072123*est

Vibration and stator current spectral analysis of induction machine operating under dynamic eccentricity
Sobra, Jan; **Belahcen, Anouar**; **Vaimann, Toomas** 2015 International Conference on Electrical Drives and Power Electronics (EDPE) : 18th International Conference, 7th Joint Slovakian-Croatian Conference : proceedings : Hotel Slovan, Tatranska Lomnica, The High Tatras, Slovakia, September 21-23, 2015 2015 / p. 285-290 : ill http://dx.doi.org/10.1109/EDPE.2015.7325307

Vibration as fault indicator in electrical machines
Farzam Far, Mehrnaz; **Belahcen, Anouar**; Arkkio, Antero; Roivainen, Janne Doctoral School of Energy and Geotechnology II :

closing conference of the project : Pärnu, Estonia, January 12-17, 2015 2015 / p. 120-125 : ill

Winding function based analytical model of squirrel cage induction motor for fault diagnostics
Asad, Bilal; **Vaimann, Toomas**; **Kallaste, Ants**; **Rassõlkin, Anton**; **Belahcen, Anouar** 2019 26th International Workshop on Electric Drives : Improvement in Efficiency of Electric Drives (IWED) : Moscow Power Engineering Institute, Moscow, Russia, 30th of January - 2nd of February 2019 : proceedings 2019 / 6 p. : ill https://doi.org/10.1109/IWED.2019.8664314

Диагностика кратных неисправностей в комбинационных схемах
Viilup, Agu; **Ubar, Raimund-Johannes**; Heiter, U. Труды по электротехнике и автоматике : сборник статей. 11 1973 / с. 89-94 : илл https://www.ester.ee/record=b2190624*est https://digikogu.taltech.ee/et/Item/d6e57925-e104-44e1-a218-c5b3110d9996

Из-за перебоев с электричеством у многих жителей Эстонии поломалась бытовая техника. Кто выплатит компенсацию?
Kappi, A-M. rus.postimees.ee 2024 Из-за перебоев с электричеством у многих жителей Эстонии поломалась бытовая техника. Кто выплатит компенсацию?

Индикатор неисправности ламп ближнего света в автомобиле
Gavrilov, Aleksei Радиолюбитель 2016 / с. 11

К вычислению изменения интенсивности отказов элементов по изменениям температуры и нагрузки
Koort, Ants Тезисы докладов Республиканской научно-технической конференции "Современные методы и устройства радиоэлектронного оборудования", посвященной Дню радио. [2], Секция: Компютерный анализ сигналов и цепей 1981 / с. 9-10 https://www.ester.ee/record=b1310795*est

Минимизация ошибок в лазерном рециркуляционном дальномере
Zahharov, Boriss; **Krusell, Urmas** Тезисы докладов III Всесоюзной конференции "Применение лазеров в технологии и системах передачи и обработки информации", 11-13 ноября 1987 г. 3, Лазерные системы передачи и обработки информации 1987 / с. 25 https://www.ester.ee/record=b1273195*est

О минимизации средного времени обнаружения неисправностей в технических устройствах
Ubar, Raimund-Johannes; Maslennikov, V.P. Вопросы управления процессами. Ч.1 1971 / с. 136-142

Построение тестов для неисправностей комбинационных схем на основе анализа ортогональных дизъюнктивных нормальных форм, представляемых альтернативными графами
Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Автоматика и телемеханика 2005 / с. 158-174 : ил http://mi.mathnet.ru/at1333

Стохастическое моделирование на ЭЦВМ возникновения отказов при малых нагрузках
Koort, Ants Тезисы докладов научно-технической конференции, посвященной Дню радио 1974 / с. 15-16 https://www.ester.ee/record=b1294751*est

Строитель Ауверескоой электростанции выплатил Enefit Power штраф в размере 130 млн евро
stena.ee 2022 Строитель Ауверескоой электростанции выплатил Enefit Power штраф в размере 130 млн евро